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# High dimensional properties of quenched noise growth models.

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We discuss the behavior of bounded slope quenched noise invasion models in high dimensions. We first observe that the roughness of such a steady state interface is generated by the combination of the roughness of the invasion process $\chi_c$ and the roughness of the underlying interface dynamics. In high enough dimension we argue that $\chi_c$ decreases to zero. This defines a critical dimension for the problem, over which it reduces to the correlated annealed dynamics, which we show to have the same roughness as the annealed equation at five dimensions. We argue that on the Cayley tree with one additional height coordinate the associated processes are fractal. The critical behavior is anomalous due to strong effects of rare events. Numerical simulations of the model on a Cayley tree and high dimensional lattices support those theoretical predictions.

Kinetic roughening of interfaces during nonequilibrium growth has attracted a lot of attraction lately. Initially the focus of the theory was on interfaces which are driven by random noise which does not depend on the position of the interface (annealed noise) [1]. A challenging problem motivated by experiments is what is the effect of disorder in the growth medium (quenched disorder). Examples of systems with such disorder are invasion of liquid in porous media and magnetic domain wall growth. It was discovered experimentally that growth in systems with quenched disorder generates exponents which are different significantly from the known annealed exponents. [1]

In growth problems there is usually a marked distinction between the behavior of the quenched noise problem and the annealed versions, and they define different universality classes. In particular the roughness exponent $\chi$ of the quenched growth is different from $\chi_a$, the roughness of the annealed model. The roughness exponent, $\chi$, is defined by $W = L^\chi$, where $W$ is the system width and $L$ is the size of the system. An important example is bounded slope growth, which may be described by the KPZ equation [2] for the annealed case [1]. The quenched model [1,3,4,5] has a different roughness. Growth in quenched disorder is characterized by the existence of a critical force level. When interfaces are driven at this critical force, critical behavior appears, in the sense that interfaces become self-affine, and have infinite correlation length, associated with processes of unbounded size.

In a set of recent papers [5,6] we pointed out that the main distinction between growth in annealed disorder and growth in quenched randomness is that the growth in quenched randomness can be decomposed into consecutive associated processes (APs), which are defined as a series of activations below a certain threshold value $f_0$ of the quenched noise field. These APs are connected sets of sites which are delimited by a network of blocking surfaces. The APs have an accompanying roughness exponent $\chi_c$ which is defined by the scaling of the height of the APs with respect to their radius. It is usually assumed that $\chi_c$ defines the roughness of the interface [3,7]; actually, it is only a lower bound for the overall roughness of the surface, not necessarily identical with it [5].

In this study we concentrate on discrete bounded slope models [3,4] which are believed to belong to the quenched KPZ universality class [5,8]. In these models the slope of the growing surface is constrained to be below a threshold value. We discuss the behavior of those models in high dimensions. We show that $\chi_c$ should go to zero in high enough dimension. We argue that the APs should become fractal objects, with a fractal dimension which remains bounded in all dimensions. To test this we present numerical analysis of systems up to six dimensions and on a Cayley tree with a height. We find that there is a nontrivial transition between the high dimensional behavior and the Cayley tree. We discuss the relationship between our conclusions and a recent analysis [7].

Analyzing the overall interface growth, the distinction between the annealed and the quenched problems becomes less important as soon as the APs become flat (or fractal). The quenched problem then becomes equivalent to the correlated annealed noise problem. We analyze the relevance of such noise. We argue that the roughness exponents of this problem are the same as the annealed KPZ exponents at 5 dimensions and above.

The discrete Buldyrev-Sneppen model [3,4], which belongs to the quenched KPZ universality class, may be defined on any space of the form $\mathcal{S} = \mathcal{L} \times \mathbf{Z}^+$, where $\mathcal{L}$ is an arbitrary substrate lattice, and $\mathbf{Z}^+$, the set of positive integers in the direction of interface growth. $\mathcal{L}$ will be defined as a hypercubic lattice $R^d$ in $d$ dimensions and as a Cayley tree in the infinite dimensional limit [9]. At each point $s$ of $\mathcal{S}$ there is a random pinning force $f(s)$ distributed uniformly between 0 and 1. The interface is a graph over $\mathcal{L}$. The growth process is as follows: the site of minimal $f$ value is activated by increasing the interface height at the point, followed by growth at nearest neighbor sites, if the local slope exceeds a threshold value.

The growth of the interface can be represented as a series of associated processes, defined as sets of activations below a threshold value $f_0$ of the quenched field $f$. An activation above $f_0$ is concludes an AP and starts a new one. The APs of $f_2$ may comprise several $f_1$ APs if $f_1 < f_2$. The largest APs are the $f_c$ APs, where $f_c$ is the critical $f$ value, *i.e.*, the largest to be activated in an infinite system. $\Delta f \equiv f_c - f_0$, measures the criticality of the APs. The APs are thus random processes characterized by the number of activations $s$, and the r.m.s radius of the projection on $\mathcal{L}$ of the process, $r_\|$.

The following scaling forms are known to be valid for $d$-dimensional APs:

$$P(s) = s^{-\tau} g(s/\Delta f^{-\nu}), \quad P(r_\|) = r_\|^{-\tau_\|} g_\|(r_\|/\Delta f^{-\nu_\|}), \tag{1}$$

and the fractal dimension $D$ of the APs is defined by

$$s \sim r_\|^D. \tag{2}$$

The scaling relations

$$\nu_\| = \nu/D \qquad \tau_\| - 1 = D(\tau - 1) \tag{3}$$

follow immediately from (1) and (2). Another scaling relation proved in [6] for 1-dimensional APs is

$$1 = \nu_\|(d + 1 - \tau_\|). \tag{4}$$

This relation reduces the number of independent static exponents to 2. When $D > d$ the APs are rough, with roughness exponent $\chi_c = D - d$. It will be shown below that those relations break down for a Cayley tree.

It is evident that the interface roughness in this system cannot be smaller than the value $\chi_c$. This is because from time to time the surface identifies with a critical surface which has this minimal roughness [5]. As an example one can consider the $1+1$ dimensional case. Since the APs are related to directed percolation their roughness is $\chi_c = 0.63$ [3]. The roughness for the annealed dynamics is $\chi_a = 0.5$, so that $\chi_c$ dominates $\chi_a$. On the other hand we should note that the roughness of the annealed KPZ equation is a lower bound on the roughness of this system. If $\chi_c = 0$, the roughness of the system will be defined by a process which will be similar to a correlated annealed KPZ dynamics. In other words:

$$\chi \geq \max(\chi_a, \chi_c). \tag{5}$$

The roughness will be generally defined by an interplay between $\chi_a$, $\chi_c$ and the correlations in the system, and can actually be larger than both $\chi$'s. It has been already observed that even in the simplest $1+1$ dimensional case the system roughness seems to be higher then $\chi_c$ [5]. For higher dimensions the effects should be much stronger since $\chi_c$ decreases. Therefore, we now focus our attention on the dependence of $\chi_c$ on the lattice dimension $d$. We note that the usual relationship $\chi = \nu_\perp/\nu_\|$ [1,3,6,7,10] is wrong in the general case, this relation applies only to $chi_c$. Furthermore if $\chi > \chi_c$ processes initiated from a flat surface such as analyzed in [7,10] will be different from the associated processes we defined here [11] in scaling properties and in statistics.

We first present an argument to show that $\chi_c$ must decrease to 0 on the Cayley tree. Consider a large cluster of radius $> r$. We want to compare the number of activated sites whose distance from a central site is $r$ to the number of activated sites with a distance of $r + 1$. Since a critical process is stationary, *i.e.*, the processes activated from sites of distance $r + 1$ are statistically the same as those from distance $r$, the ratio of the number of sites on the two shells should be asymptotically 1 for a critical cluster. Therefore the number of sites on the critical cluster grows more slowly than exponentially, in other words, it is fractal, with a fractal dimension $D_\infty$. Studying the rules of growth indicates that whenever $\chi_c$ is positive, the APs cannot be fractal, since rough clusters have a typical width $r_\perp \sim s^{\chi_c/D}$, which through avalanches prevents the formation of holes with diameter smaller than $r_\perp$. For $d \leq d_c$ the APs may be multiply connected, but not fractal. APs with $\chi_c = 0$ are objects with order 1 thickness, which may fractalize. We can therefore conclude that $\chi_c$ is 0 on the Cayley tree.

We have shown that $\chi_c$ decreases from 0.63 to 0 when $d$ increases from 1 to $\infty$. It is very natural to presume that the decrease of $\chi_c$ as a function of $d$ is monotonic, and this is indeed verified by numerical simulations but is not critical to the following argumentation. This scenario for the dependence of $\chi_c$ on $d$ motivates a definition of an upper critical dimension $d_c$ where $\chi_c = 0$. $d_c$ marks the transition to fractal APs. We can state that $d_c \leq D_\infty \leq \infty$. In fact, additional arguments, involving dynamic exponents indicate that $d_c \leq 6$ [11]. Most of the preceding arguments on the behaviour of the AP as a function of $d$ may be generalized to other growth models such as quenched Edwards-Wilkinson growth.

Fractal APs in this model will be unusual due to rare events in which a single site is activated several times, creating large, compact avalanches which are exceptional in the overall structure of the AP. These events, although exponentially rare, can dominate the tail of the distribution of the APs, and thus alter the scaling forms (1). We demonstrate this mechanism for the breakdown of the scaling form for $P(s)$ on the Cayley tree. Let $\bar{s}(h)$ be the expectation for the size of an AP given that a single site is of height $h$. For $h$ larger then the average height $\bar{s}$ must grow exponentially,

$$\bar{s}(h) \sim \mu^h, \tag{6}$$

with $\mu$ larger or equal to the coordination number of the lattice minus 1. $\mu$ is an increasing function of $f_0$

for $f_0 \leq f_c$. On the other hand the probability that a site in an $f_0$ AP reaches a height $h$ should decrease like $\tilde{f}^h$ with $\tilde{f}$ larger than, but of the order of $f_0$, and also an increasing function of $f_0$. A rough estimate for the probability to activate an AP of size $s$ is

$$\mathsf{P}(\bar{s}(h) \leq s \leq \bar{s}(h+1)) \sim \tilde{f}^h; \tag{7}$$

combining with (6) we get

$$P(s) \sim s^{\log \tilde{f}/\log \mu - 1} \equiv s^{\tau(f_0)}. \tag{8}$$

On the Cayley tree, the distribution of the APs is always a power law, with a non-universal $f_0$-dependent exponent. This is in accord with the findings of [7]. This behavior is in marked contrast to the normal critical behavior (1). The difference should be attributed to the strength of exponentially rare events, which dominate the large $s$ tail of the distribution. The main conclusion (8) does not depend on the assumption of localized distribution. A more detailed analysis of bounded slope models on the Cayley tree will be given elsewhere [11].

A similar analysis may be carried out for finite dimensional systems whenever the APs are flat or fractal, so that an unusually large height at one site can modify the local structure of an AP. In contrast to the Cayley tree, avalanches stemming from such rare events are expected to grow only as a power of $h$, $s \sim h^{\tilde{d}}$, so that the large $s$ tail of $P(s)$ should decay as a stretched exponential,

$$P(s) \sim s^{-\tau} \exp(-as^{1/\tilde{d}}), \tag{9}$$

instead of a power law as in the Cayley tree. The dependence of $a$ on $f_0$ is yet to be investigated. Eq. (8) indicates that the mean cluster size does not diverge near $f_c$. However, our previous scaling relations (3) and (4) and also simulations in high dimensions indicate that $\langle s \rangle \sim |f_c - f_0|^{-\gamma}$, with $\gamma \geq 1$. Hence the transition from low dimensional behavior to high dimensional behavior is anomalous. We conjecture that the scaling form (8) is obtained as an infinite dimensional limit of (9).

We now turn our attention to the scaling of the growing interface as a whole. Above $d_c$ the APs are flat, and growth becomes similar to the annealed process, with the source correlation derived from the distribution and structure of the flat or fractal APs. In this regime $\chi$ will remain positive and equal to that of annealed KPZ [1,2]

$$\partial_t h(\mathbf{x},t) = \nabla^2 h(\mathbf{x},t) + \lambda(\nabla h(\mathbf{x},t))^2 + \eta(\mathbf{x},t), \tag{10}$$

where $h$ is the height and the random source $\eta$ has spatial correlations derived from the statistics of the APs. This motivates the definition of a second critical dimension $d_i$, such that $\chi_a = \chi$ for $d > d_i$. $d_i$ rather than $d_c$ is the relevant critical dimension for the overall roughness.

When $d > d_c$, $\eta$ is Gaussian and, and its correlation function is derived as follows: Since the APs are not correlated (for $f_0 = f_c$, see [6]), the noise at two points is correlated if and only if the two sites were activated in the same AP. Therefore the source correlation may be estimated by the probability of such an event, which may be estimated as

$$\begin{aligned} \langle \eta(\mathbf{x})\eta(\mathbf{y})\rangle &\sim P(r_\parallel \geq |\mathbf{y}-\mathbf{x}|)|\mathbf{y}-\mathbf{x}|^{D-d} \\ &\sim |\mathbf{y}-\mathbf{x}|^{D(2-\tau)-d}. \end{aligned} \tag{11}$$

We now analyze the effects of those correlations. Let $h(\mathbf{k},\omega) = \int d^d\mathbf{x}dt\, h(\mathbf{x},t)e^{i\mathbf{k}\cdot\mathbf{x}+i\omega t}$ with $\eta(\mathbf{k},\omega)$ defined similarly. We also define the response function $G(\mathbf{k},\omega)\delta(\mathbf{k}+\mathbf{k}')\delta(\omega+\omega') = \langle \delta h(\mathbf{k},\omega)/\delta\eta(\mathbf{k}',\omega')\rangle$. The scaling form of $G$ is $G(\mathbf{k},\omega) = k^{-z}g(\omega/k^z)$, and the noise correlation is $\langle \eta(\mathbf{k},\omega)\eta(\mathbf{k}',\omega')\rangle = k^\alpha\delta(\mathbf{k}+\mathbf{k}')\delta(\omega+\omega')$, where $\alpha = D(\tau-2)$. We define the "bare" height field as

$$h_0(\mathbf{k},\omega) = G(\mathbf{k},\omega)\eta(\mathbf{k},\omega) \tag{12}$$

If the roughness of $h_0$ dominates the annealed white noise roughness $\chi_a$, the system roughness $\chi$ must be larger than $\chi_a$. The bare correlation is

$$\begin{aligned} \langle h_0(\mathbf{k},\omega)h_0(\mathbf{k}',\omega')\rangle &= G(\mathbf{k},\omega)G(\mathbf{k}',\omega')\,\langle \eta(\mathbf{k},\omega)\eta(\mathbf{k}',\omega')\rangle \\ &\sim k^{-2z+\alpha}g(\omega/k^z)^2\delta(\mathbf{k}+\mathbf{k}')\delta(\omega+\omega'), \end{aligned} \tag{13}$$

and the simultaneous correlation is given by

$$k^{-2z+\alpha}\int d\omega g(\omega/k^z)^2 \sim k^{-z+\alpha}. \tag{14}$$

From the correlation in (14) we get an effective bare roughness $2\chi_0 = \max(z-\alpha-d, 0)$.

The condition for irrelevance becomes

$$2\chi > z - \alpha - d. \tag{15}$$

(15) is always satisfied for uncorrelated noise ($\alpha = 0$), and also reproduces the known condition for irrelevance of the noise correlation in 1 dimension, $\alpha > -1/2$ [1]. Numerical simulations give $d_c \sim 6$ (see below), and values for $D$ and $\tau$ given in table 1. Inequality (15) is satisfied for those values, so $d_i \leq d_c$.

We performed numerical simulations of the Buldyrev-Sneppen model in order to examine the previous theoretical scenario. The simulations consisted of growth in a hypercubic lattice of dimension 1 to 6, and growth on a Cayley tree as an effective infinite dimensional lattice. The growth on finite-dimensional lattices was simulated using the constant current algorithm starting from a flat surface. The search for the global minimum which is required in this approach was coded in an efficient manner, so that about $10^{10}$ activations were simulated in each case. The main computational constraint, however, was memory area, which dictated lattices of small sides, down to 16 in 6 dimensions, where there was a small but observable scaling range. The simulations were performed with periodic boundary conditions.

The exponents $\tau_\parallel$, $\gamma$ and $D-d$ were measured. They are presented in table 1. These exponents are not independent, and $\gamma$, for example, is obtainable from the other two using relations (1,4). The calculated values of $\gamma$ agree with the measured values of $\gamma$, thus providing a consistency check on the simulations. (A possible source of deviations is a weak size dependence of the exponents.)

It is evident from table 1 that the APs become flat at 6 dimensions, so $d_c \sim 6$. The measured $\chi_c$ becomes equal to numerical measurements of $\chi_a$ [12] at 4 dimensions within numerical accuracy. Since $\chi_c \ll 1$ at 5 dimensions, it is probably safe to use the criterion (15) for relevance of noise correlation for KPZ roughness. The criterion is satisfied so that $4 \leq d_i \leq 5$. Independent measurements of the overall interface roughness [10] indicate that this is indeed the case, see table 1. There is no numerical indication of an upper critical dimension above which the exponents don't change.

Simulations were performed also of the Cayley tree version of the model as a limit of high dimensional systems. Since clusters are expected to be fractal, of a volume growing as $\ell^D$ with the cluster length $\ell$, it is very inefficient to simulate the process on the full Cayley tree. Therefore we simulated the processes on a background of a flat blocked surface punctured at one point. As discussed above these processes might have different scaling than APs on the Cayley Tree because of the strong dependence of the distributions on height fluctuations [11,14] but the general predictions still apply. The clusters were grown with a constant driving force, until either the surface became blocked, or the size of the cluster exceeded a certain memory limit (about $2 \times 10^6$ sites).

To examine the distribution of AP sizes we simulated $10^9$ clusters for each value of the driving force $f_0$, on a Cayley tree with coordination number 3. As expected, we find that the transition is anomalous in the sense that the probability distribution function is a power law for all values of $f_0 \leq f_c$, of the form (8), with no apparent cutoff. The value of $f_c$ was calculated by estimating the number of infinite avalanches initiated by the process. An equivalent definition is that $\tau(f_c) = 2$. It is found that $f_c = .141 \pm .001$. The measured value of $\tau$ decreases with $f_0$ and can be fitted with $\tau(f_0) - 2 \sim (f_c - f_0)^{1/2}$. This is the same dependence as in the different Cayley tree realization used in [7]. The reason for this seems to be that the APs are flat so that the differences between the models become irrelevant. The relationship between the models will be discussed elsewhere [11]. The measurement of $D$ is more difficult, but a significant dependence on $f_0$ could be observed. The measured value at $f_c$ was $D = 6.5 \pm 0.5$. This translates to twice the value in high-dimensional hyper-cubic lattices [13].

In this paper we reached an understanding of the structure of quenched noise growth as a function of dimensionality. We identified the role of the underlying KPZ dynamics in determining the roughness of the growing interface. The concept of AP introduced in Ref [6] remains useful in this analysis. The main idea is that those processes possess an intrinsic roughness $\chi_c$ and that they interact via annealed KPZ dynamics. The system roughness $\chi$ is a result of this interplay. We show that $\chi_c$ decreases with dimension to 0 at $d = d_c$, and moreover the fractal dimension of the APs saturates to a finite value $D_\infty$. Hence, above $d_c$ the random sequence of APs is equivalent to correlated noise acting on annealed KPZ equation. Analyzing this effect we show that above 4 dimensions $\chi = \chi_a$. Those general considerations apply to any of the various models for quenched disorder discussed in the literature [1,11]. Finally, we have shown that the critical behavior of the APs is anomalous on the Cayley tree, and made some conjectures as to the transition to this behavior from finite dimensions.

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| $d$ | $f_c$ | $\gamma$ | $D-d$ | $\tau_\parallel$ | $\gamma_{\text{calc}}$ | $\chi$ [5,10] |
|---|---|---|---|---|---|---|
| 1 | .4610(2) | 2.03(3) | .64(2) | 1.42(2) | 2.09 | 0.67 |
| 2 | .2002(2) | 1.53(2) | .52(2) | 2.11(2) | 1.58 | 0.50 |
| 3 | .1148(3) | 1.29(2) | .40(2) | 2.86(2) | 1.34 | 0.38 |
| 4 | .0785(5) | 1.21(1) | .24(3) | 3.58(2) | 1.17 | 0.27 |
| 5 | .0583(2) | 1.13(2) | .07(3) | 4.22(3) | 1.03 | 0.25 |
| 6 | .0445(5) | 1.08(2) | .00(5) | 5.05(5) | 1 | 0.2 |

TABLE I. Scaling exponents of interface growth, as measured from the results of numerical simulations, except $\gamma_{\text{calc}}$ which was calculated from $\chi_c$ and $\tau_\parallel$ using (3) and (4), and $\chi$. The numbers in parenthesis are errors in the last digit.